

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: )  
 HIROSHI AOTO ET AL. )  
 Application No.: 10/769,765 )  
 Filed: February 3, 2004 )  
 For: DIELECTRIC FILM STRUCTURE, )  
 PIEZOELECTRIC ACTUATOR USING )  
 DIELECTRIC ELEMENT FILM )  
 STRUCTURE AND INK JET HEAD : October 13, 2005



Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450

RESPONSE TO ELECTION OF SPECIES REQUIREMENT

Sir:

In response to the Office Action mailed September 13, 2005, which set forth an election of species requirement, Applicants elect Species I. Applicants submit that Claims 1-4, 10 and 13 read on the elected species.

Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202)530-1010. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

A handwritten signature in black ink, appearing to read "B. L. Klock".

Attorney for Applicants  
 Brian L. Klock  
 Registration No. 36,570

FITZPATRICK, CELLA, HARPER & SCINTO  
 30 Rockefeller Plaza  
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 DWP/BLK/mls

03500.017883



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: )  
HIROSHI AOTO ET AL. ) : Examiner: R. Dicht  
Application No.: 10/769,765 ) : Group Art Unit: 2853  
Filed: February 3, 2004 ) :  
For: DIELECTRIC FILM STRUCTURE, )  
PIEZOELECTRIC ACTUATOR USING :  
DIELECTRIC ELEMENT FILM )  
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Alexandria, VA 22313-1450

SECOND INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. §1.56 and in accordance with the practice under 37 C.F.R. §§1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. A copy of each listed document (other than the U.S. Patents) is enclosed.

These documents may be pertinent because they were cited in a European Search Report issued in a counterpart application on September 1, 2005. A copy of the Search Report is enclosed.

FORMAL MATTERS

No fee is believed due; however, any fee required in connection with this paper should be charged to Deposit Account No. 06-1205.

CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that an initialed copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should continue to be directed to our below-listed address.

Respectfully submitted,



Attorney for Applicants  
Brian L. Klock  
Registration No. 36,570

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>03500.017883</b>		APPLICATION NO. <b>10/769,765</b>			
		APPLICANT <b>HIROSHI AOTO ET AL.</b>					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) October 13, 2005		FILING DATE <b>February 3, 2004</b>		GROUP <b>2853</b>			
<b>U.S. PATENT DOCUMENTS</b>							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	<b>5,265,315</b>	<b>11/1993</b>	<b>Hoisington et al.</b>				
	<b>4,584,590</b>	<b>04/1986</b>	<b>Fischbeck et al.</b>				
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
	<b>0 656 429 A</b>	<b>06/1995</b>	<b>Europe</b>			<b>Yes</b>	
<b>OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	<b>OGAWA et al., "Controlling The Crystal Orientations of Lead Titanate Thin Films", Japanese Journal of Applied Physics, Tokyo, Japan, vol. 30, no. 9B, September 1, 1991, pps. 2145-2148</b>						
	<b>LIN et al., "Epitaxial Growth of Pb(Zr<sub>0.2</sub>Ti<sub>0.8</sub>)O<sub>3</sub> On Si and its Nanoscale Piezoelectric Properties", Applied Physics Letters, American Institute of Physics, New York, USA, vol 78, no. 14, April 2, 2001, pps. 2034-2036</b>						
<b>EXAMINER</b>		<b>DATE CONSIDERED</b>					

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

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Sheet 1 of 1